MAY 1 8 2007

DOCKET NO.: 4685

TED STATES PATENT AND TRADEMARK OFFICE

IN THE MATTER OF THE APPLICATION FOR PATENT

OF: Shinsuke FUJIWARA et al.

ART UNIT: 2811

SERIAL NO.: 10/829,306

CONF. NO.: 5680

FILED: April 20, 2004

EXAMINER: A. O. ARENA

FOR: GROUP II-VI LIGHT EMITTING DEVICE HAVING I-TYPE BARRIER LAYER DIRECTLY BETWEEN ACTIVE LAYER AND P-TYPE CLADDING LAVER

COMMISSIONER FOR PATENTS P.O. BOX 1450 ALEXANDRIA, VA 22313-1450

May 14, 2007

INFORMATION DISCLOSURE STATEMENT WITH CERTIFICATE OF MAILING

Dear Sir:

- 1) Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98 applicants enclose a Fifth Form PTO-1449, copies of references AX to AH2 cited thereon, English Abstracts as indicated on Form PTO-1449, and copies as well as English translations of two Japanese Office Actions issued on April 3, 2007 in two counterpart Japanese applications.
- In accordance with 37 C.F.R. 1.97(d), this IDS is being filed 2) before payment of the issue fee, includes the required statement under 37 C.F.R. 1.97(e)(1) (see next paragraph), and is accompanied by a Credit Card Payment Form (PTO-2038) to cover the required fee of \$180.00.

85/21/2007 MWULDGE1 00000002 10829306 81 FC:1866 180,00 00

4685/WFF:ks

- The undersigned attorney hereby certifies that each item of information contained in this Information Disclosure Statement
 was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months
 prior to the filing of this Information Disclosure Statement.
- 4) References AV to AX are in English. References AY to AH2 are accompanied by English Abstracts. Reference AY corresponds to AX, AA2 corresponds to AV, and AD2 corresponds to AW, from which the relevance can be determined in English. Therefore no further discussion of the references is necessary.
- Office Actions show why the Japanese Examiner found references
 AY to AH2 to be relevant to the counterpart Japanese patent
 applications. The Japanese Examiner's statements are not
 ratified as accurate or adopted by applicant, but they are
 submitted for the US Examiner's consideration as to the possible
 relevance of the references. The additional references cited in
 the Japanese Office Actions have already been submitted in our
 Information Disclosure Statements dated November 7, 2005 and
 January 9, 2007.
- 6) The Examiner is requested to consider all references of record, return an initialed copy of the enclosed Form PTO-1449, and ensure that all references of record are printed on any patent issuing from this application.

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 A Response to the Final Office Action of April 23, 2007 will be filed in due course.

> Respectfully submitted, Shinsuke FUJIWARA et al. Applicant

WFF:ks/4685
Enclosures: postcard,
Form PTO-2038,
Fifth Form PTO-1449,
11 references,
10 English abstracts,
copies and Engl. translations
of 2 Japanese Office Actions

Walter F. Fasse Patent Attorney

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P.O. Box 726 Hampden, ME 04444-0726

CERTIFICATE OF MAILING:

I hereby certify that this correspondence with all indicated enclosures is being deposited with the U. S. Postal Service with sufficient postage as first-class mail, in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on the date indicated below.

Name: Karin Smith - Date: May 14, 200

Sheet 1 of 1 FIFTH IDS LIST OF REFERENCES CITED BY APPLICANT							al No.: 29,306	
C.	(FOR	4 PEQ-1449)	•	Inventor(s): Shinsuke FU	TIWARA e	t al.		
(FORM PTG-1449) DATED: May 147, 2007				U.S. Filing Date: April 20, 2004			Art Unit: 2811	
	THE STATE OF THE S	MAY 18 2007 G	υ.	S. PATENT DOCUMENTS				
*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME		Cl.	Sub-	Fil.
	AV	5,362,974	11/1994	Irikawa et al.		-	-	T-
	AW	5,519,722	05/1996	Iwata		-	-	-
			FORE	IGN PATENT DOCUMENTS				
		DOCUMENT NO.	DATE	COUNTRY	C1.	Sub- Cl.	Eng	lish
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	AY	04-273491	09/1992	Japan	-	-	Abstract,	
	AZ	06-097572	04/1994	Japan	-	-	Abstract	
	AA2	06-244509	09/1994	Japan	-	-	Abstract,	
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	AG2	08-162481	06/1996	Japan	-	-	Abstract	
	AH2	10-083999	03/1998	Japan	-	-	Abstract	
				OTHER DOCUMENTS				
1								
EXAMINER	s sic	NATURE		DATE CONSIDERED				

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEF 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.